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GE Industrial Systems

Functional Testing Specification

*Renewal Services
Louisville, KY*

LOU-GED-IC3606SIxx

Test Procedure for a IC3606 Input Card

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A	Initial release	R. Duvall	12/18/02
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DATE 12-18-02	DATE	DATE	DATE

Functional test procedure for a Card

1. SCOPE

1.1 This is a functional testing procedure for a IC3606 Input Card.

2. STANDARDS OF QUALITY

2.1 Refer to the current revision of the IPC-A-610 standard for workmanship standards.

3. APPLICABLE DOCUMENTS

3.1 The following document(s) shall form part of this specification to the extent specified herein. Unless otherwise indicated, the latest issue shall apply.

3.1.1 UUT Documentation Folder

4. ENGINEERING REQUIREMENTS

4.1 Equipment Cleaning

4.1.1 Equipment should be clean and free of debris prior to applying power unless performing an initial check. Refer to the local documented procedures for cleaning guidelines.

4.2 Equipment Inspection

4.2.1 Equipment should be visually inspected for any defects prior to applying power. This inspection should include the following as a minimum:

4.2.1.1 Wires broken or cracked

4.2.1.2 Terminal strips / connectors broken or cracked

4.2.1.3 Loose wires

4.2.1.4 Components visually damaged

4.2.1.5 Capacitors leaking

4.2.1.6 Solder joints damaged or cold

4.2.1.7 Circuit board burned or de-laminated

4.2.1.8 Printed wire runs burned or damaged

5. EQUIPMENT REQUIRED

5.1 The following equipment is required to perform the process requirements. Equipment may be substituted provided that all accuracy's and test ratios are equivalent or better.

Qty	Reference #	Description
1		Fluke 85 DMM (or Equivalent)
1		O-Scope
1		90 VDC Power Supply
1		12 VDC Power Supply
1	H188546	Input Card Connector

6. TESTING PROCESS

6.1 Setup

6.1.1 Replace all Optocouplers prior to final testing

6.1.2 Wire Test Connections per Figure 1



Note: Replace ALL optocouplers prior to final testing.

6.2 Testing Procedure

6.2.1 Apply 12 VDC power

6.2.2 Input Test

6.2.2.1 Connect +Scope lead to pin 5 on UUT.

6.2.2.2 Apply 90 VDC power and verify IL1 Illuminates.

6.2.2.3 Verify a clean +10 VDC signal on the O-Scope.

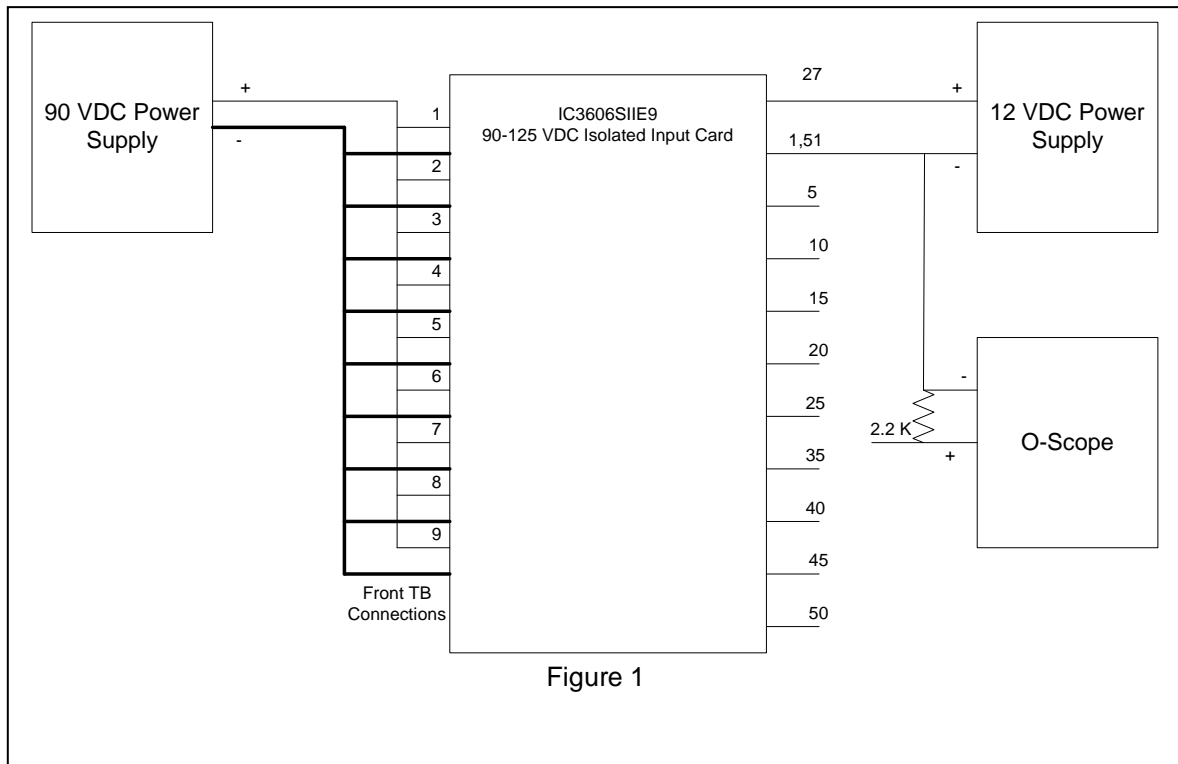
6.2.3 Repeat Input Test for each input using the information in Table 1.

Circuit #	+ DC	- DC	Indicator	Output Pin
1	1	10	IL1	5
2	2	10	IL2	10
3	3	10	IL3	15
4	4	10	IL4	20
5	5	10	IL5	25
6	6	10	IL6	35
7	7	10	IL7	40
8	8	10	IL8	45
9	9	10	IL9	50
Table 1				

6.3 ***TEST COMPLETE***

7. NOTES

Test Connections



8. Oscilloscope Verification Examples:

Fig. 1

Fig. 2

